

Chemical-state-discriminated hard X-ray photoelectron diffraction study for polar InN

Yoshiyuki Yamashita¹, Anli Yang¹, Masaaki Kobata², Keisuke Kobayashi²

¹ National Institute for Materials Science, 1-1 Namiki, Tsukuba, 305-0044, Japan

² Quantum Beam Science, Japan Atomic Energy Agency, 1-1-1 Koto, Sayo, 679-5148, , Japan
yamashita.yoshiyuki@nims.go.jp

InN has received great research attention because of the small bandgap (~ 0.7 eV) and superior electrical transport properties. As a wurtzite crystal lacks inversion symmetry along c-axis direction, In-polar and N-polar InN exhibit different properties. Therefore, investigation of near-surface structure and electronic states of polar InN films are important to fully realize their potential. Due to the element and chemical state specificity and the larger probing depth, hard X-ray photoelectron diffraction (HXPd) was used to investigate the near-surface structures of polar InN films [1].

The HXPd system consists of a monochromatic Cr K α source (5414.7 eV), a high energy version of the VG SCIENTA R4000 10 kV analyzer with wide acceptance objective lens. The angle acceptance of the combined objective lens and the analyzer is $\pm 35^\circ$ with an angular resolution of 0.5° . The total energy resolution was 1 eV. In this study, the polar angle θ is defined to be zero for the photoemission direction normal to a sample surface. The θ -dependent sensitivity of the analyzer, was calibrated using an amorphous GeSbTe sample.

Figure 1 shows the HXPd patterns from In $3d_{5/2}$ and N $1s$ core levels of In-polar and N-polar InN. The patterns were different from each other and then they were compared with the simulation results using a multiple-scattering cluster model[2], which is shown in Fig.1. It was found that the near-surface structure of the In-polar InN film was close to the ideal wurtzite structure. On the other hand, on the N-polar InN film, defects-rich surface was formed. In addition, the existence of the In-polar domains was observed in the HXPd patterns.

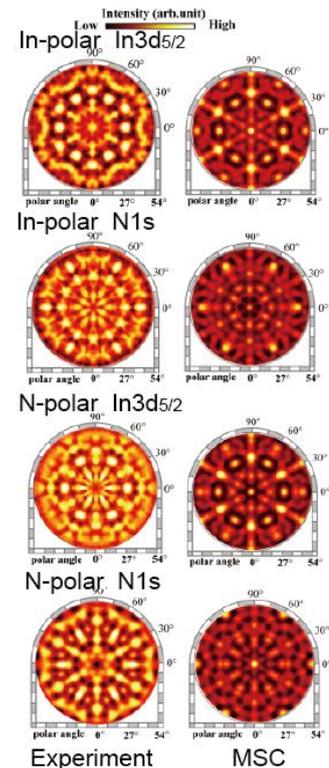


Fig.1: In3d and N1s HXPd for In-polar and N-polar InN

References:

- [1] A. Yang, Y. Yamashita, et al., Appl. Phys. Lett. **102**, 031914 (2013).
- [2] T. Matsushita, et al., J. Electron Spectrosc. Relat. Phenom. **178**, 195 (2010).